

# ARGOS 2.1

## Specifications

Category	ARGOS 2.1	Comments
<b>Test diameter</b>	Ø 55 mm	
<b>Nominal resolution</b>	3.5 µm	Object-side pixel pitch
<b>Smallest specification according to ISO 10110-7*</b>	5/ 1×0.025; L1×0.01; E 0.063	Evaluation as required by the standard down to 16% of specified dig size and 25% of specified scratch size.
<b>Smallest visible defects*</b>	< 1.5 µm	Small defects will be assigned the minimum grade number 0.004.
<b>Precision of the size measurement*</b>	< 2 µm	Mean standard deviation of measured defect sizes for 30 repetitions with the same calibration sample.
<b>Surface material</b>	glass, metal, semiconductors, plastics, crystals	Polished surfaces with optical quality; others on request
<b>Test duration flat substrate</b>	ca. 5 s	The evaluation time depends on the specification and quality of the surface.
<b>Lens test duration</b>	ca. 45 s per mm of sag	For curved parts, a high density focus stack is recorded.
<b>Maximum part size</b>	Ø 150 mm	Note that only the inner Ø 55 mm can be inspected.
<b>Maximum surface slope</b>	60°	Slopes < 45° are ideal, high slopes have a larger risk of measurement artifacts.
<b>System size</b>	ca. 300 × 300 × 500 mm	L × W × H, control unit and PC are separate.

\* The achievement of these specifications can only be guaranteed with the original ARGOS calibration sample with known defects of defined width and depth.